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1 Application of a mesh experiment for a proton beam onto the charge-coupled device

Tsunemi, H.; Miki, M.; Miyata, E.;

Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 5 , Oct. 2004

Pages:2288 - 2292

[\[Abstract\]](#) [\[PDF Full-Text \(648 KB\)\]](#) IEEE JNL

2 New seed geometry for growth of low dislocation synthetic quartz

Shinohara, A.H.; Iano, M.C.; Suzuki, C.K.;

Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on , Volume: 47 , Issue: 5 , Sept. 2000

Pages:1199 - 1203

[\[Abstract\]](#) [\[PDF Full-Text \(424 KB\)\]](#) IEEE JNL

3 Longitudinal and transverse feedback systems for PLS storage ring

Kang, H.S.; Hwang, W.H.; Park, H.J.; Kim, D.T.; Huang, J.Y.; Nam, S.H.;

Particle Accelerator Conference, 2001. PAC 2001. Proceedings of the 2001 , Volume: 2 , 18-22 June 2001

Pages:1616 - 1618 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(271 KB\)\]](#) IEEE CNF

4 Effects of nitrogen additive gas on sidewall passivation in W/TiN/high-k dielectric gate etching

Jae-Young Kim; Yu-Kwon Kim; Kwang-Ok Kim; Chang Ju Choi; Jin Woong Kim;

Microprocesses and Nanotechnology Conference, 2000 International , 11-13 July 2000

Pages:210 - 211

[\[Abstract\]](#) [\[PDF Full-Text \(132 KB\)\]](#) IEEE CNF

5 Nonlinear longitudinal dynamics studies at the ALS

Byrd, J.M.; Cheng, W.-H.; Zimmermann, F.;

Particle Accelerator Conference, 1997. Proceedings of the 1997 , Volume: 2 , 12-16 May 1997

Pages:1514 - 1516 vol.2

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1 On reduction of Moire pattern distortion in digital diagnostic X-ray imaging

Slump, C.H.; Klaren, W.; Jansen, E.; Herrmann, O.E.;

Image Processing and its Applications, 1992., International Conference on , 7-9 Apr 1992

Pages:494 - 497

[\[Abstract\]](#) [\[PDF Full-Text \(408 KB\)\]](#) **IEE CNF**

2 Observations of the plasma in a two-wire Z-pinch

Camacho, J.R.; Beg, F.N.; Dangor, A.E.; Ross, I.;

Plasma Science, 1998. 25th Anniversary. IEEE Conference Record - Abstracts. 1998 IEEE International on , 1-4 June 1998

Pages:318

[\[Abstract\]](#) [\[PDF Full-Text \(92 KB\)\]](#) **IEEE CNF**

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1 **Mean-squared error analysis of an adaptive notch filter**

Nishimura, S.; Kim, J.K.; Hirano, K.;

Circuits and Systems, 1989., IEEE International Symposium on , 8-11 May 1989

Pages:732 - 735 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(212 KB\)\]](#) **IEEE CNF**

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S3	304	382/280.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 16:42
S4	846	382/275.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/28 15:08
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S10	92303	noise\$1ratio or (noise adj ratio) or SNR	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 16:53
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S14	6	S2 and S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 17:05
S15	598208	notch or band\$1pass or band\$1stop	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 17:06
S16	1847290	filter\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 17:06

S17	9	S15 and S16 and S12 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/28 10:31
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S58	2774	S57 same S56	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:10

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